

Notice of References Cited	Application/Control No. 09/767,514	Applicant(s)/Patent Under Reexamination GUEST, JOHN DEREK	
	Examiner David E. Bochna	Art Unit 3679	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,851,036	12-1998	Vanesky, Frank W.	285/369
	B	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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